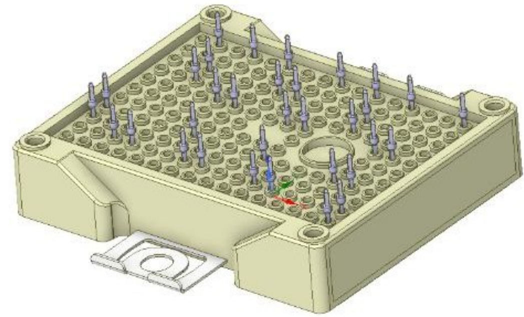
IGBT - Field Stop,Trench,Soft Fast Recovery Diode

650V/150A



Features

- Electrical features
  - V_{CES} = 650 V
  - $I_{C\ nom}$ = 150 A / I_{CRM} = 300 A
  - Increased blocking voltage capability up to 650 V
  - Low inductive design
  - Low switching losses
  - Low $V_{CE,sat}$
- Mechanical features
  - Al_2O_3 substrate with low thermal resistance
  - Compact design
  - Rugged mounting due to integrated mounting clamps

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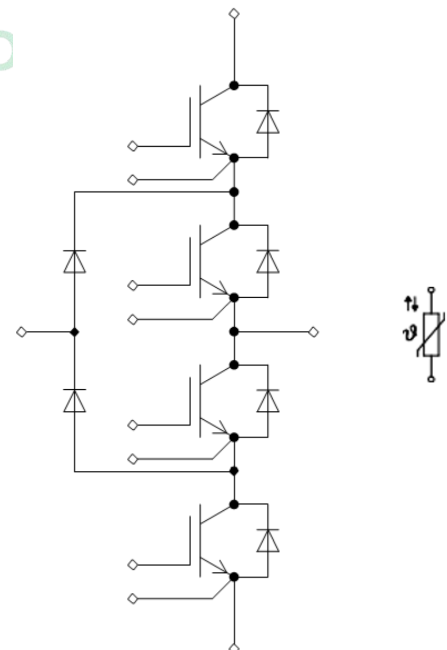
Potential applications

- Three-level applications
- Solar applications
- UPS systems



Device	Package	Shipping
SPM150V065P2BS	P2B	TRAY

Table 1. ABSOLUTE MAXIMUM RATINGS (T_J = 25°C unless otherwise noted) (Note 1)

Rating	Symbol	Value	Unit
IGBT (T1, T2, T3, T4)			
Collector-Emitter Voltage	V_{CES}	650	V
Gate-Emitter Voltage Positive Transient Gate−Emitter Voltage (T_{pulse} = 5 s, D < 0.10)	V_{GE}	±20 30	V
Continuous Collector Current @ T_C = 80°C	I_C	100	A
Pulsed Peak Collector Current @ T_C = 80°C (T_J = 175°C)	$I_{C(Pulse)}$	200	A
Maximum Power Dissipation (T_J = 175°C)	P_{tot}	350	W
Minimum Operating Junction Temperature	T_{JMIN}	−40	°C
Maximum Operating Junction Temperature (Note 2)	T_{JMAX}	150	°C
IGBT INVERSE DIODE (D1, D2, D3, D4)			
Peak Repetitive Reverse Voltage	V_{RRM}	650	V
Continuous Forward Current @ T_C = 80°C	I_F	90	A
Repetitive Peak Forward Current (T_J = 175°C)	I_{FRM}	180	A
Maximum Power Dissipation (T_J = 175°C)	P_{tot}	350	W
Minimum Operating Junction Temperature	T_{JMIN}	−40	°C
Maximum Operating Junction Temperature	T_{JMAX}	150	°C
NEUTRAL POINT DIODE (D5, D6)			
Peak Repetitive Reverse Voltage	V_{RRM}	650	V
Continuous Forward Current @ T_C = 80°C	I_F	100	A
Repetitive Peak Forward Current (T_J = 175°C)	I_{FRM}	200	A
Maximum Power Dissipation (T_J = 175°C)	P_{tot}	350	W
Minimum Operating Junction Temperature	T_{JMIN}	−40	°C
Maximum Operating Junction Temperature	T_{JMAX}	150	°C

Any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

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Table 2. STORAGE AND INSULATION PROPERTIES (T_J = 25°C unless otherwise noted) (Note 1)

Rating	Symbol	Value	Unit

STORAGE PROPERTIES

Operating Temperature under Switching Condition	T_{VJOP}	−40 to 150	°C
Storage Temperature Range	T_{stg}	−40 to 125	°C

INSULATION PROPERTIES

Isolation Test Voltage, t = 1 s, 50 Hz (Note 2)	V_{is}	4000	V_{RMS}
Creepage Distance		6.7	mm
Comparative Tracking Index	CTI	>200	

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1. **Refer to ELECTRICAL CHARACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.**
2. **4000 VACRMS for 1 second duration is equivalent to 3333 VACRMS for 1 minute duration.**

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
IGBT (T1, T2, T3, T4) CHARACTERISTICS						
Collector-Emitter Cutoff Current	I_{CES}	V_{GE} = 0 V, V_{CE} = 650 V	–	-	25	μA
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	V_{GE} = 15 V, I_C = 150 A, T_J = 25°C	–	1.8	-	V
		V_{GE} = 15 V, I_C = 150 A, T_J = 150°C	–	2.2	–	
Gate-Emitter Threshold Voltage	$V_{GE(TH)}$	V_{GE} = V_{CE}, I_C = 4 mA	5.0	5.4	5.6	V
Gate Leakage Current	I_{GES}	V_{GE} = ±20 V, V_{CE} = 0 V	–	–	±1.0	μA
Turn-on Delay Time	$t_{d(on)}$	T_J = 25°C V_{CE} = 300 V, I_C = 150 A V_{GE} = −9 V, 15 V, R_{Gon} = 5 Ω, R_{Goff} = 5 Ω	–	22.4	–	ns
Rise Time	t_r		–	43.2	–	
Turn-off Delay Time	$t_{d(off)}$		–	155.2	–	
Fall Time	t_f		–	32	–	
Turn-on Switching Loss per Pulse	E_{on}		–	2.42	–	mJ
Turn-off Switching Loss per Pulse	E_{off}		–	2.45	–	
Turn-on Delay Time	$t_{d(on)}$	T_J = 150°C V_{CE} = 300 V, I_C = 150 A V_{GE} = −9 V, 15 V, R_{Gon} = 5 Ω, R_{Goff} = 5 Ω	–	23.2	–	ns
Rise Time	t_r		–	45.5	–	
Turn-off Delay Time	$t_{d(off)}$		–	167	–	
Fall Time	t_f		–	36.2	–	
Turn-on Switching Loss per Pulse	E_{on}		–	3.65	–	mJ
Turn-off Switching Loss per Pulse	E_{off}		–	3.82	–	
Input Capacitance	C_{ies}	V_{CE} = 20 V, V_{GE} = 0 V, f = 1 MHz	–	8485	–	pF
Output Capacitance	C_{oes}		–	610	–	
Reverse Transfer Capacitance	C_{res}		–	70	–	
Integrated Gate Resistor	R_g		–	2	–	Ω
Thermal Resistance – Chip-to-Case	R_{thJC}		–	0.24	–	℃/W
NEUTRAL POINT DIODE (D5, D6) CHARACTERISTICS						
Diode Forward Voltage	V_F	I_F = 150 A, T_J = 25°C	–	1.5	1.95	V
		I_F = 150 A, T_J = 150°C	–	1.3	–	
Reverse Recovery Time	t_{rr}	T_J = 25°C V_{CE} = 300 V, I_C = 150 A V_{GE} = −9 V, 15 V, R_G = 5 Ω	–	123	–	ns
Reverse Recovery Charge	Q_{rr}		–	4312	–	nC
Peak Reverse Recovery Current	I_{RRM}		–	70	–	A
Peak Rate of Fall of Recovery Current	di/dt		–	2.757	–	A/ns
Reverse Recovery Energy	E_{rr}		–	675	–	μJ
Thermal Resistance – Chip-to-Case	R_{thJC}		–	0.37	–	℃/W

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit

IIGBT INVERSE DIODE (D1, D2, D3, D4) CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Diode Forward Voltage	V_F	I_F = 90 A, T_J = 25°C	–	1.35		V
		I_F = 90 A, T_J = 150°C	–	1.13	–	
Reverse Recovery Time	t_{rr}	T_J = 25°C VCE = 300 V, IC = 150 A V_{GE} = −9 V, 15 V, R_G = 5 Ω	–	123	–	ns
Reverse Recovery Charge	Q_{rr}		–	4312	–	nC
Peak Reverse Recovery Current	I_{RRM}		–	70	–	A
Peak Rate of Fall of Recovery Current	di/dt		–	2.757	–	A/ns
Reverse Recovery Energy	E_{rr}		–	675	–	µJ
Thermal Resistance – Chip-to-Case	R_{thJC}		–	0.37	–	℃/W

THERMISTOR CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Nominal Resistance	R_{25}	T = 25°C	–	5	–	kΩ
B-value	$B_{25/50}$	B-value (25℃/50℃), tolerance ±2%	–	3375	–	K

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

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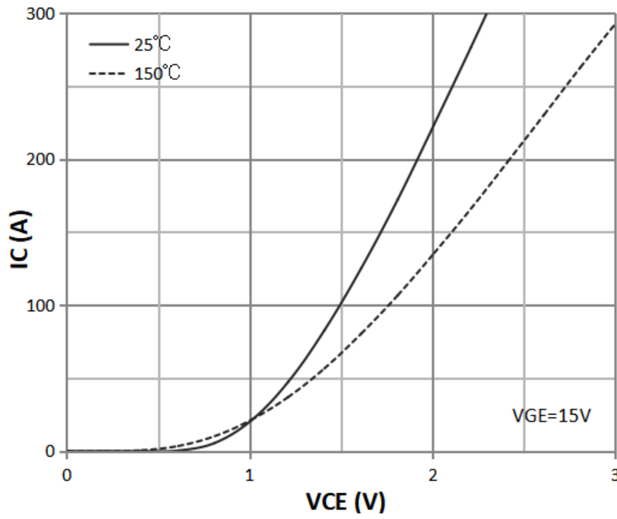


Figure 1. Typical Output Characteristics IGBT

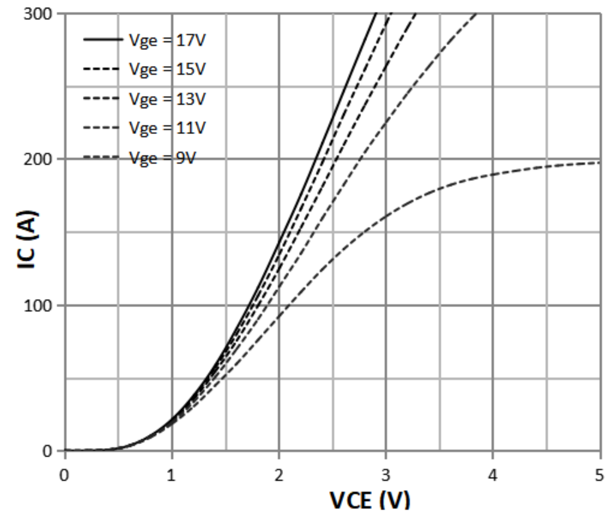


Figure 2. Typical Output Characteristics IGBT

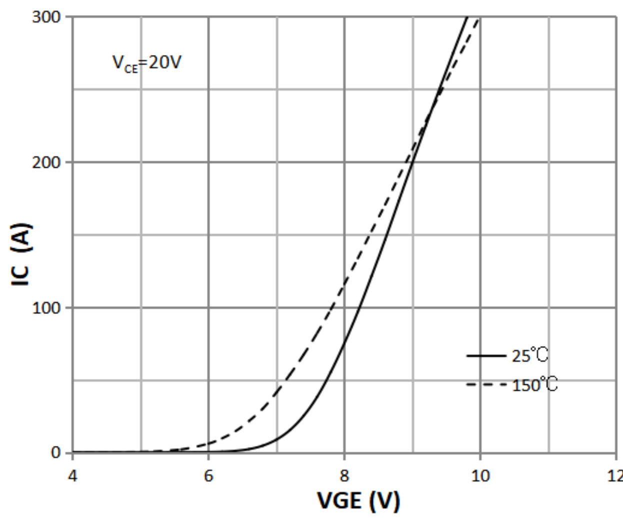


Figure 3. Typical Transfer Characteristics IGBT

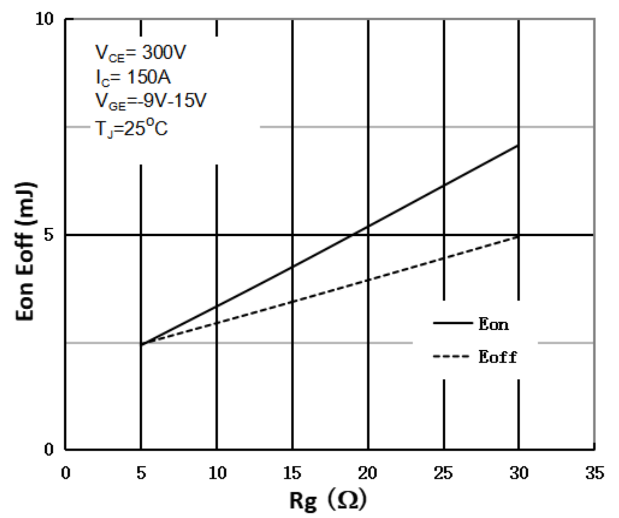


Figure 4. Switching Energy vs Gate Resistor IGBT

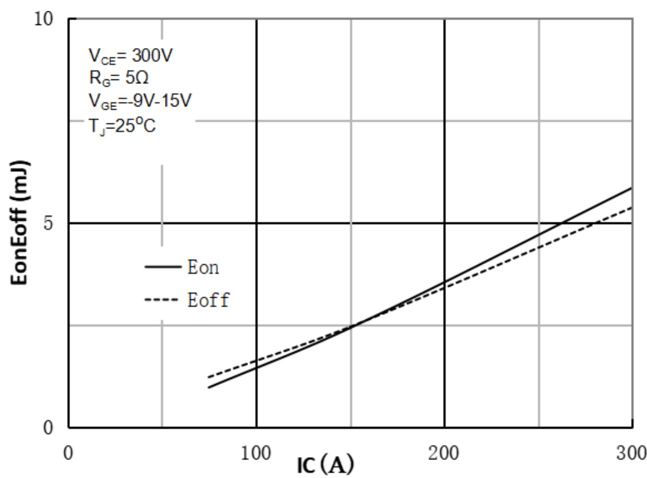


Figure 5. Switching Energy vs Collector Current IGBT

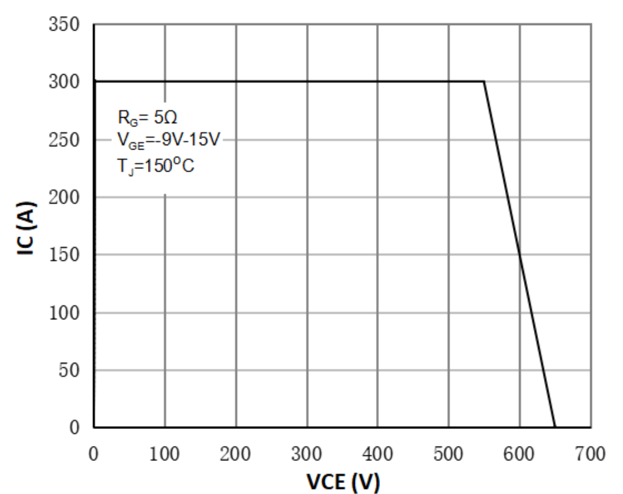


Figure 6. Reverse Biased Safe Operating Area IGBT

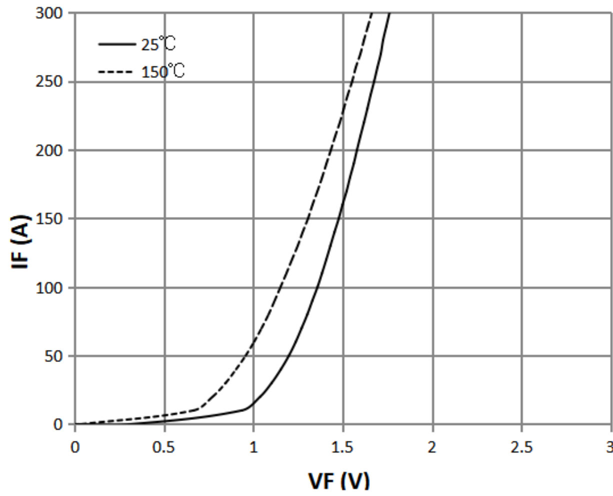


Figure 7. Diode Forward Characteristics

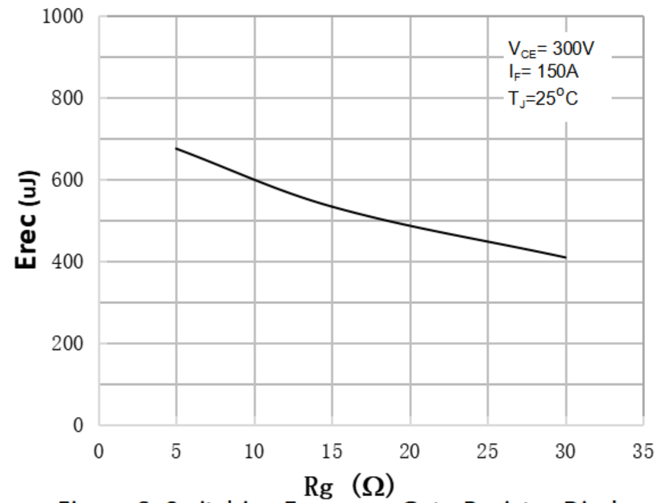


Figure 8. Switching Energy vs Gate Resistor Diode

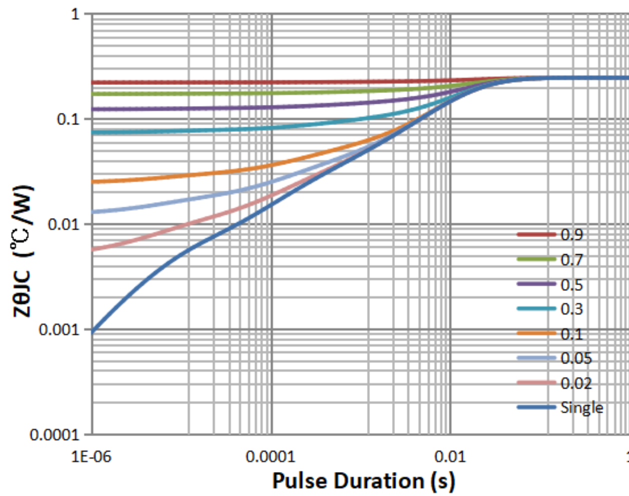


Figure 9. IGBT Transient Thermal Impedance, Junction to Case

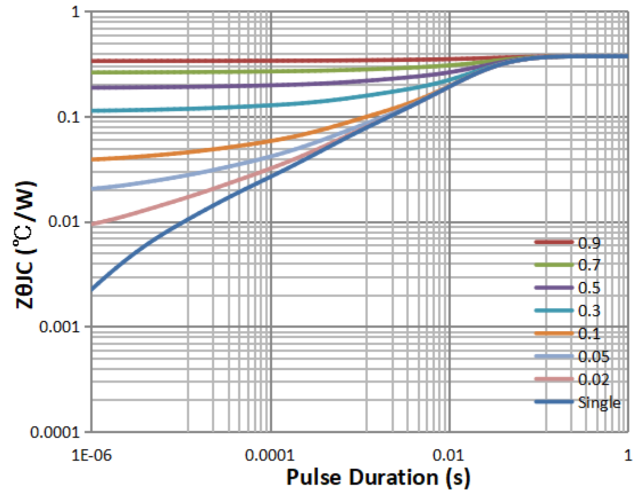
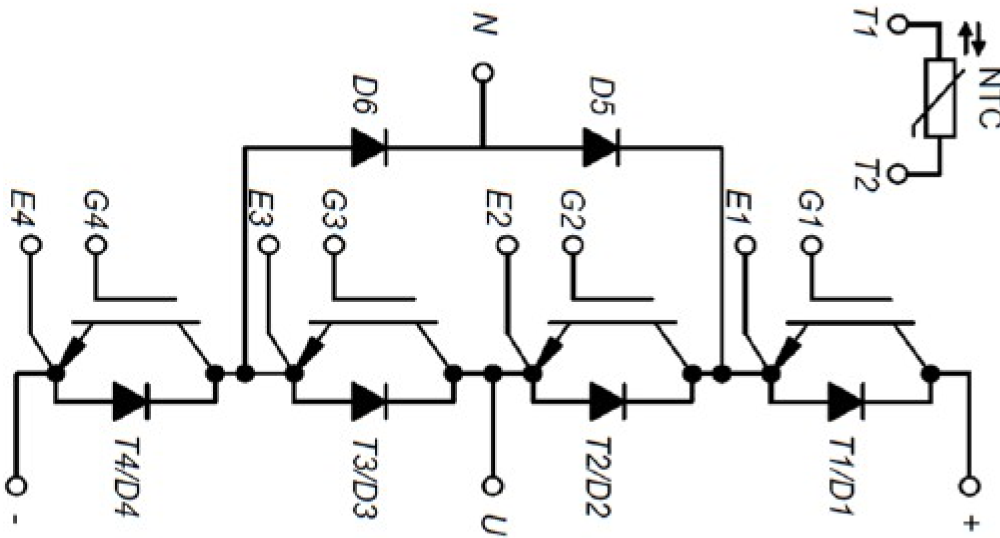
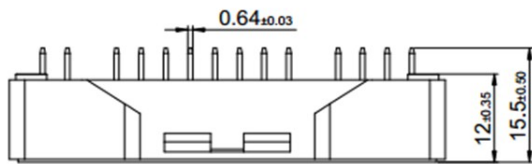
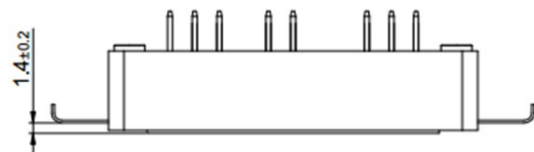
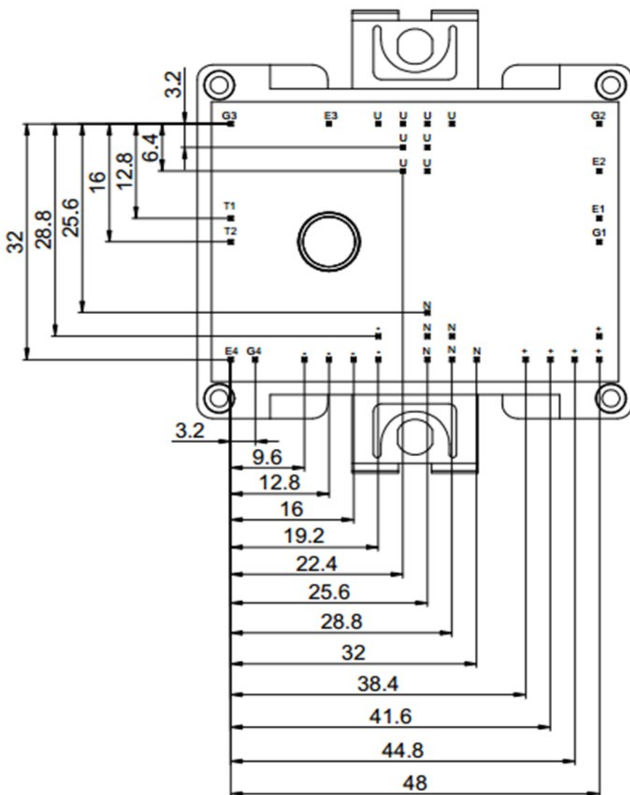


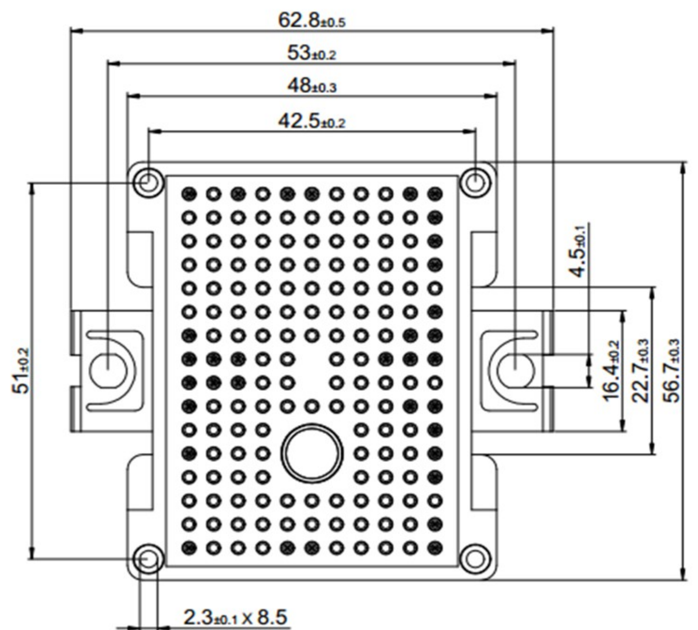
Figure 10. Diode Transient Thermal Impedance, Junction to Case


N
D6
D5
T1
NTC
T2
E4
G4
E3
G3
E2
G2
E1
G1
T4/D4
T3/D3
T2/D2
T1/D1
-
U
+


0.64±0.03
12±0.35
15.5±0.50


1.4±0.2


3.2
6.4
12.8
16
25.6
28.8
32
3.2
9.6
12.8
16
19.2
22.4
25.6
28.8
32
38.4
41.6
44.8
48


62.8±0.5
53±0.2
48±0.3
42.5±0.2
51±0.2
4.5±0.1
16.4±0.2
22.7±0.3
56.7±0.3
2.3±0.1 x 8.5